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TO 70R1309022\*1680#1703 P.09/39  
Sheet 1 of 1

Form PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE <b>LIST OF ART CITED BY APPLICANT</b> (Use several sheets if necessary)				ATTY. DOCKET NO. M122-1680	SERIAL NO. 09/825,664		
				APPLICANT Micron Technology, Inc.			
				FILING DATE April 3, 2001	GROUP 2829		
<b>U.S. PATENT DOCUMENTS</b>							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	5,886,863	03/23/02	MAGASAKI et al			
	AB						
	AC						
	AD						
<b>OTHER REFERENCES (Including Author, Title, Date, Published Pages, Etc.)</b>							
	AE						
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	AK						
	AL						
<b>EXAMINER</b> <i>Mah Nguyen</i>				<b>DATE CONSIDERED</b> 07/23/2002			
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Form PTO-1449  JAN 28 2002 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF ARTS CITED BY APPLICANT (Use several sheets if necessary)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. MI22-1680	SERIAL NO. 09/825,664		
		APPLICANT David R. Hembree					
		FILING DATE April 3, 2001	GROUP 2829				
U.S. PATENT DOCUMENTS							
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	3,440,407	4/22/69	Golstos et al.			
	AB	3,614,345	10/19/71	Quinn			
	AC	3,683,306	8/8/72	Bulthius et al.			
	AD	4,332,081	6/1/82	Francis			
	AE	4,518,944	5/21/85	Faris			
	AF	4,703,555	11/3/87	Hubner			
	AG	5,141,334	8/25/92	Castles			
	AH	5,347,869	9/20/94	Shie et al.			
	AI	5,406,109	4/11/95	Whitney			
	AJ	5,436,646	7/25/95	McArthur et al.			
	AK	5,446,437	8/29/95	Bantien et al.			
FOREIGN PATENT DOCUMENTS							
		Document Number	Date	Country	Class	Subclass	Translation
							Yes
VN	AL	2336778	7/1977	France			
VN	AM	56-12521	2/1981	Kobayashi, Japan			
VN	AN	2-268462	11/1990	Yamanishi, Japan			
	AO						<i>thorough</i>
	AP						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
VN	AR	Application Guide Temperature Sensors, Welslow Electrical Manufacturing Company Catalog, pp. 775-778, 1992/1993.					
VN	AS	In-Situ survey System of Resistive and Thermoelectric Properties of Either Pure or Mixed Materials in Thin Films Evaporated Under Ultra High Vacuum, Lechevalier, Leffre, Richou, Serre, & Gousset, J. Phys. III France, Vol. 5, pp. 409-418, 04/95 (Abstract only).					
VN	AT	Temperature Metrology for CD Control in DUV Lithography, Jeffrey Parker and Wayne Renken, pp. 111-112, 114, 116, 09/17/97.					
EXAMINER <i>M. Nguyen</i>				DATE CONSIDERED 07/23/2002			
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				FILING DATE April 3, 2001	GROUP 2829

## U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	5,612,574	3/18/97	Summerfelt et al.			
	AB	5,719,333	2/17/98	Hosoi et al.			
	AC	5,831,333	11/3/98	Malladi et al.			
	AD	5,919,548	7/6/99	Barron et al.			
	AE	5,551,283	9/3/96	Manaka et al.			
	AF	5,492,011	2/20/96	Amano et al.			
	AG						
	AH						
	AJ						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AK							
	AL							
	AM							
	AN							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

VN	AP	"NTC and PTC Thermistors"; <a href="http://www.thermodisc.com/ntcptc.html">http://www.thermodisc.com/ntcptc.html</a> ; 1/7/98; 2 pages.					
VN	AR	"DI-5B35 Linearized 4-Wire RTD Input"; <a href="http://www.dataq.com/di5b35.html">http://www.dataq.com/di5b35.html</a> ; 1/7/98; 2 pages.					
VN	AS	"RTD"; <a href="http://www.misensors.com/rtds.html">http://www.misensors.com/rtds.html</a> ; 1/7/98; 3 pages.					
VN	AT	"Low Cost Thermal-Ribbon (TM) uses thin film RTD"; <a href="http://www.minco.com/s17624nr.html">http://www.minco.com/s17624nr.html</a> ; 1/7/98; 1 page.					
VN	AU	"Silicon Processing for the VLSI Era"; Volume 1 - Process Technology; Second Edition; S. Wolf et al.; 2000; pps 22-25 and pps. 841-845.					
EXAMINER	<i>Mark Nguyen</i>			DATE CONSIDERED 07/23/2002			

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<u>VN</u>	AA	5,325,052	6/28/1994	Yamashita				
	AB	5,708,250	1/13/98	Benjamin et al.				
	AC	5,557,215	9/17/96	Saeki et al.				
	AD							
<u>OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)</u>								
	AE							
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				U.S. PATENT DOCUMENTS			
*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
V/N	AA	6,004,471	12/21/1999	Chuang			
V/N	AB	5,550,526	8/27/1996	Mottahead			
	AC						
	AD						
<b>OTHER REFERENCES</b> (including Author, Title, Date, Pertinent Pages, Etc.)							
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